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The invention relates to the field of measuring technology and can be used in measuring instruments that use sensors based on nanostructured semiconductor oxides.

The device for measuring the parameters of a sensor based on nanostructured semiconductor oxides in the range of the order of microwatts comprises an adjustable reference voltage source, connected in series to a test sensor and a standard resistance, the total voltage drop across the sensor and the standard resistance, and separately, the voltage drop across the standard resistance being applied to the inputs of two analog-to-digital converters of a microcontroller through two operational amplifiers, the outputs of the microcontroller are connected by a digital-to-analog converter to the input of the adjustable reference voltage source and to a screen for displaying the obtained results.

Claims: 1

Fig.: 2